


<b>Search Notes</b> 	<b>Application/Control No.</b> 10777363	<b>Applicant(s)/Patent Under Reexamination</b> SUMITOMO ET AL.
	<b>Examiner</b> Mackowey, Anthony	<b>Art Unit</b> 2624

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	103, 199, 209, 217, 220	4/2/07	AM

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor Name Search in PALM	4/2/07	AM
EAST Text Search (US-PGPUB, USPAT, USOCR, EP0, JPO, DERWENT, IBM_TDB) - see search history printout	4/2/07	AM
Text Search IEEE Xplore- see search history printout	4/2/07	AM
Consulted Samir Ahmed, Primary Examiner 2624 regarding pattern recognition and template matching with open curves	4/3/07	AM

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>